TOSHIBA Field Effect Transistor Silicon P Channel MOS Type ( $L^2-\pi$ -MOSV)

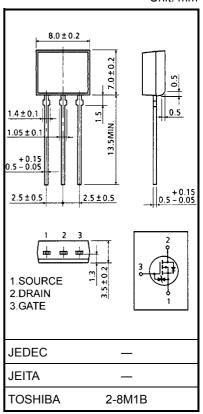
# 2SJ378

## Relay Drive, DC–DC Converter and Motor Drive Applications

- 4 V gate drive
- Low drain-source ON resistance  $R_{DS}(ON) = 0.16 \Omega$  (typ.)
- High forward transfer admittance  $|Y_{fs}| = 4.0 \text{ S (typ.)}$
- Low leakage current  $: I_{DSS} = -100 \ \mu A \ (max) \ (V_{DS} = -60 \ V)$
- Enhancement-mode :  $V_{th} = -0.8 \sim -2.0 V (V_{DS} = -10 V, I_D = -1 mA)$

#### Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	-60	V	
Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)		V <sub>DGR</sub>	-60	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC (Note 1)	۱ <sub>D</sub>	-5	А	
	Pulse(Note 1)	I <sub>DP</sub>	-20	А	
Drain power dissipatio	n	PD	1.3	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	273	mJ	
Avalanche current		I <sub>AR</sub>	-5	А	
Repetitive avalenche energy (Note 3)		E <sub>AR</sub>	0.13	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 0.54 g (typ.)

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient	R <sub>th (ch−a)</sub>	96.1	°C / W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:  $V_{DD}$  = -25 V,  $T_{ch}$  = 25°C (initial), L = 14.84 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = -5 A

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution. Unit: mm

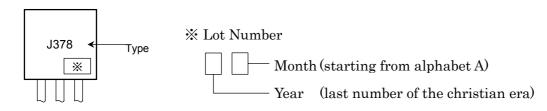
Electrical Characteristics (Ta = 25°C)

Charao	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V		_	±10	μA
Drain cut-off cu	rrent	I <sub>DSS</sub>	$V_{DS} = -60 \text{ V}, V_{GS} = 0 \text{ V}$	_		-100	μA
Drain-source br	eakdown voltage	V (BR) DSS	I <sub>D</sub> = -10 mA, V <sub>GS</sub> = 0 V	-60	_	_	V
Gate threshold v	voltage	V <sub>th</sub>	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1 \text{ mA}$	-0.8		-2.0	V
Drain-source ON resistance		R <sub>DS (ON)</sub>	V <sub>GS</sub> = -4 V, I <sub>D</sub> = -2.5 A	_	0.24	0.28	Ω
			$V_{GS}$ = -10 V, I <sub>D</sub> = -2.5 A	_	0.16	0.19	32
Forward transfe	r admittance	Y <sub>fs</sub>	$V_{DS}$ = -10 V, I <sub>D</sub> = -2.5 A	2.0	4.0	—	S
Input capacitance	ce	C <sub>iss</sub>		-	630	_	
Reverse transfer capacitance		C <sub>rss</sub>		_	95	_	pF
Output capacitance		Coss			290	_	
Switching time	Rise time	tr	$V_{\rm GS} \stackrel{\rm OV}{\sim}$	_	25	_	
	Turn-on time	t <sub>on</sub>	$V_{GS} \stackrel{0V}{\xrightarrow{-10V}} \stackrel{I_{D} = -2.5A}{} V_{OUT}$ $R_{L} = 12\Omega$ $V_{DD} = -30V$	_	45	_	20
	Fall time	t <sub>f</sub>		_	55	_	- ns
	Turn-off time	t <sub>off</sub>	Duty $\leq 1\%$ , t <sub>w</sub> =10 $\mu$ s	_	200	_	
Total gate charge (Gate-source plus gate-drain)		Qg		_	22	_	
Gate-source charge		Q <sub>gs</sub>	V <sub>DD</sub> ≈ -48 V, V <sub>GS</sub> = -10 V, I <sub>D</sub> = -5 A	_	16	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>			6	_	

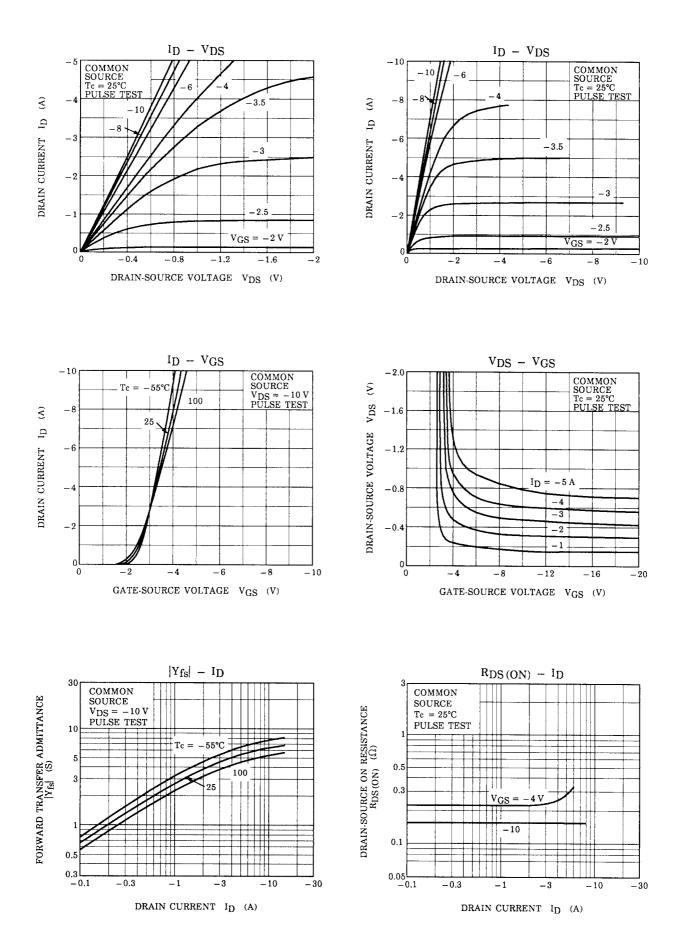
#### Source–Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	-5	А
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	—	_	_	-20	А
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = -5 A, V <sub>GS</sub> = 0 V	_	_	1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = −5 A, V <sub>GS</sub> = 0 V dI <sub>DR</sub> / dt = 50 A / μS		80		ns
Reverse recovery charge	Qrr		_	0.1	_	μC

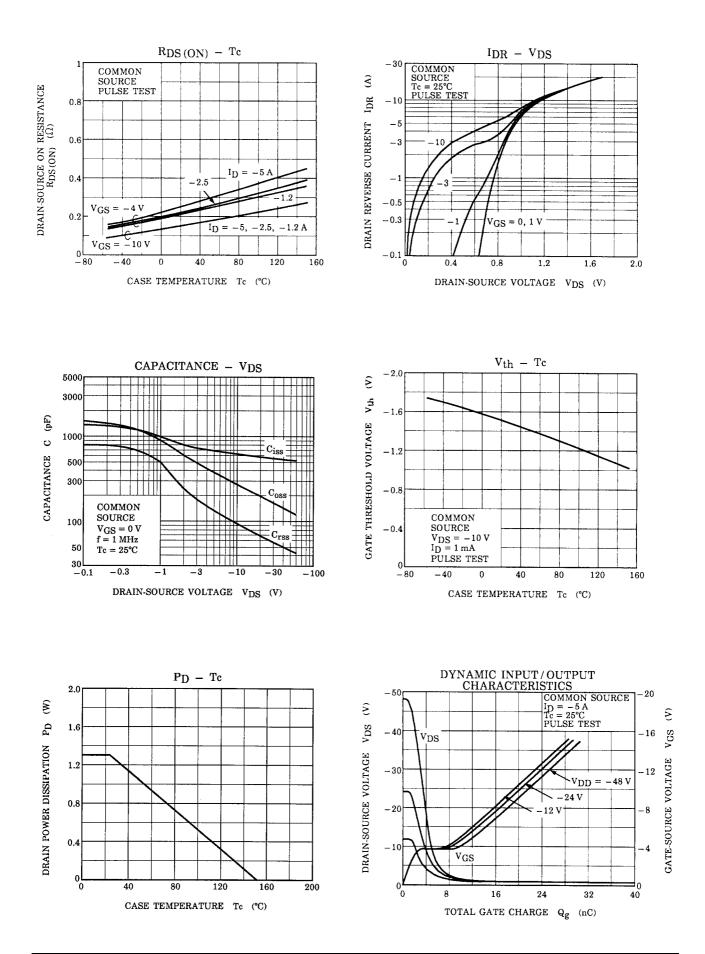
#### Marking

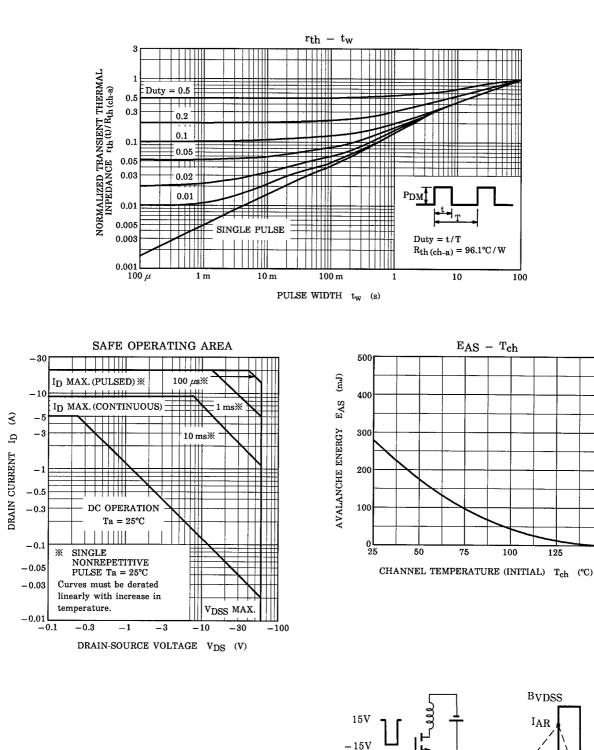


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VDS

 $v_{DD}$ 

WAVE FORM

 $E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}}\right)$ 

TEST CIRCUIT

 $V_{DD} = -25V, L = 14.84mH$ 

150

 $R_G = 25\Omega$ 

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